Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/796,011	TAKE, KEIJIRO		
Examiner	Art Unit		
Tri H. Phan	2661		

SEARCHED					
Class	Subclass	Date	Examiner		
370	320,335, 342,441, 479,203	12/6/2004	TP		
370	350,332	12/6/2004	TP		
370	508-510	12/6/2004	TP		
375	200	12/6/2004	ΤP		
Updated	search	6/17/2005	TP		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
EAST, IEEE, Internet searched	12/6/2004	TP
Updated search	6/17/2005	TP
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